

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10565770	LOEKER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Lee, Rebecca	4181

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
525	165	01/14/2009	/mmd/

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor's name search in eDAN and EAST		
Assignee search in EAST		
EAST search in USPAT USPGPUB USOCR EPO JPO DERWENT	01/14/2009	/mmd/

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/M. D./  
Examiner.Art Unit 1796